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THERMAL RESISTIVITY OF LAYERED ⁴He FILMS ON ZYX GRAPHITE BELOW 2 K

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Thermal resistance and vapor pressure isotherms were taken near superfluid onset for ultrathin helium films adsorbed on a ZYX graphite wafer between $1-2\,\mathrm{K}$ and 3-7 atomic layers. Our data are consistent with previous graphite onsets and are compatible with a current model of film droplet formation. Overlap of thermal resistance curves at 1.19 and 139 K is believed to be associated with discrete layering effects of 2D superfluid film properties.

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PHOTOEMISSION STUDIES OF CLEAN AND OXYGEN-COVERED Pt 6(111) X (100) *

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Employing the enhanced sensitivity obtained by using synchrotron radiation near the Cooper minimum for the 5d valence electrons, we have located the oxygen 2p and 2s levels for oxygen chemisorbed on a Pt 6(111) \times (100) crystal. We find the oxygen 2p level located -6 eV with a FWHM of 3 eV and the 2s at -21.6 eV. A factor of four difference in saturation coverage is measured between temperatures of 300 and 120 K, but the position and width of the 2p level is independent of temperature. We observe also the $1b_1$ orbital of weakly adsorbed H_2O molecules, which has pure O 2p parentage; from the intensity of this orbital, we are able to suggest why it is difficult to observe the oxygen 2p signal at low photon energies. In addition, we note a strong preferential attenuation in the Pt states near E_f for the adsorbed H_2O in spite of the weak nature of the bond.

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AIDER (ANGLE-OF-INCIDENCE DERIVATIVE ELLIPSOMETRY AND REFLECTOMETRY) – IMPLEMENTATION AND APPLICATION Victor M. BERMUDEZ

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An experimental arrangement is described whereby spectroscopic polarization—modulation ellipsometry can be extended to the measurement of both the usual parameters ψ and Δ and